

D²PAK

G(1)

Figure 1. Internal schematic diagram

D(2, TAB)

S(3) 🖒

STB36NM60ND, STW36NM60ND

Datasheet - production data

R_{DS(on)}

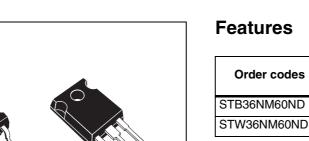
max.

0.110 Ω

ID

29 A

Automotive-grade N-channel 600 V, 0.097 Ω typ., 29 A FDmesh[™] II Power MOSFETs (with fast diode) in D²PAK and TO-247 packages



TO-247

Designed for automotive applications and AEC-Q101 gualified

V_{DSS} @T_J

max.

650 V

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance
- Extremely high dv/dt and avalanche capabilities

Applications

• Automotive switching applications

Description

These FDmesh[™] II Power MOSFETs with intrinsic fast-recovery body diode are produced using the second generation of MDmesh[™] technology. Utilizing a new strip-layout vertical structure, these revolutionary devices feature extremely low on-resistance and superior switching performance. They are ideal for bridge topologies and ZVS phase-shift converters.

Table 1. Device summary

AM01475v1

Order codes	Marking	Package	Packaging
STB36NM60ND	36NM60ND	D ² PAK	Tape and reel
STW36NM60ND	36NM60ND	TO-247	Tube

October 2013

DocID023785 Rev 3

This is information on a product in full production.

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1 Electrical ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	600	V
V _{GS}	Gate- source voltage	± 25	V
I _D	Drain current (continuous) at $T_{C} = 25 \ ^{\circ}C$	29	А
۱ _D	Drain current (continuous) at $T_C = 100 \ ^\circ C$	18	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	116	А
P _{TOT}	Total dissipation at $T_C = 25 \ ^{\circ}C$	190	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope	40	V/ns
T _{stg}	Storage temperature	- 55 to 150	O
Т _Ј	Max. operating junction temperature	150	

1. Pulse width limited by safe operating area

2. I $_{SD}$ \leq 29 A, di/dt \leq 600 A/µs, V $_{DD}$ = 80% V $_{(BR)DSS}$, V $_{DSPeak}$ < V $_{(BR)DSS}$

Table 3. Thermal data

Symbol	Parameter	Value		Unit
		D ² PAK	TO-247	Onit
R _{thj-case}	Thermal resistance junction-case max	0.66		°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	50		°C/W
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb max	30		°C/W

1. When mounted on FR-4 board of 1 inch², 2 oz Cu.

Table 4. Avalanche characteristics

Symbol Parameter		Parameter	Value	Unit
	I _{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by ${\rm T_J}$ max)	x) 7	
	E_{AS} Single pulse avalanche energy (starting T _J = 25 °C, I _D = I _{AR} , V _{DD} = 50 V)		110	mJ



2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

		Sie 5. On/on states				
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_{\rm D} = 1$ mA, $V_{\rm GS} = 0$	600			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = 600 V$ $V_{DS} = 600 V, T_{C} = 125 °C$			1 100	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V_{GS} = 10 V, I _D = 14.5 A		0.097	0.110	Ω

Table 5. 0	Dn/off	states
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Tab		6	D,	ma	mia
lap	ie.	о.	U	/na	mic

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Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	2785	-	pF
C _{oss}	Output capacitance	V _{DS} = 50 V, f = 1 MHz,	-	168	-	pF
C _{rss}	Reverse transfer capacitance	V _{GS} = 0	-	5	-	pF
C _{oss eq.} ⁽¹⁾	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0 \text{ to } 480 \text{ V}$	-	438	-	pF
t _{d(on)}	Turn-on delay time		-	30	-	ns
t _r	Rise time	V _{DD} =300 V, I _D = 14.5 A R _G = 4.7 Ω, V _{GS} = 10 V	-	53.4	-	ns
t _{d(off)}	Turn-off delay time	$n_{G} = 4.7 \ \Omega_{2}, \ v_{GS} = 10 \ v_{GS}$ (see <i>Figure 16</i> and <i>21</i>)	-	111	-	ns
t _f	Fall time		-	61.8	-	ns
Qg	Total gate charge	V _{DD} = 480 V, I _D = 29 A,	-	80.4	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 10 V,	-	16	-	nC
Q _{gd}	Gate-drain charge	(see Figure 17)	-	41.4	-	nC
R _g	Gate input resistance	f=1 MHz , open drain	-	2.87	-	Ω

C_{oss eq} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain current Source-drain current (pulsed)		-		29 116	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 29 A, V _{GS} = 0	-		1.6	V
t _{rr}	Reverse recovery time	I _{SD} = 29 A, V _{DD} = 60 V	-	175		ns
Q _{rr}	Reverse recovery charge	di/dt=100 A/µs	-	1.4		μC
I _{RRM}	Reverse recovery current	(see Figure 18)	-	16		А
t _{rr}	Reverse recovery time	$I_{SD} = 29 \text{ A}, V_{DD} = 60 \text{ V}$	-	255		ns
Q _{rr}	Reverse recovery charge	di/dt=100 A/µs, T _{.1} = 150 °C	-	2.6		μC
I _{RRM}	Reverse recovery current	(see Figure 18)	-	20		А

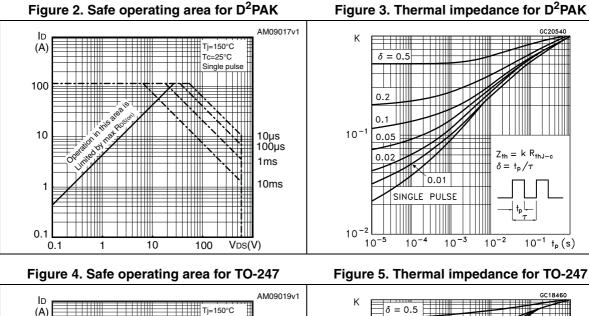
Table 7. Source drain diode

1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = $300 \ \mu s$, duty cycle 1.5%.



2.1 Electrical characteristics (curves)



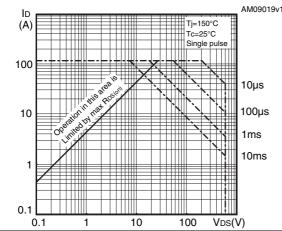


Figure 6. Output characteristics

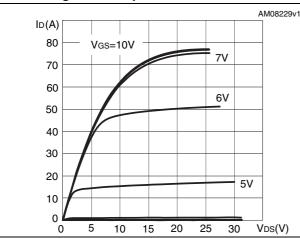


Figure 7. Transfer characteristics

 10^{-3}

 10^{-2}

 $Z_{th} = k R_{thJ-c}$ $\delta = t_p / \tau$

 $t_{p}(s)$

 10^{-1}

0.2

10-

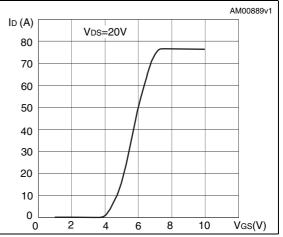
10

10⁻³

0.1

SINGLE PULSE

 10^{-4}





Vds

Vgs

(V)

12

10

8

6

4

2 0

0

Figure 8. Gate charge vs gate-source voltage

VDD=480V

ID=29A

AM08231v1

VDS

(V)

500

400

300

200

100

0

Figure 9. Static drain-source on-resistance AM08232v1 RDS(on) (Ω) 0.102 VGS=10V 0.100 0.098 0.096 0.094 0.092 0.090 4 8 12 16 20 24 28 ID(A) 0

Figure 10. Capacitance variations

10 20 30 40 50 60 70 80 90 Qg(nC)

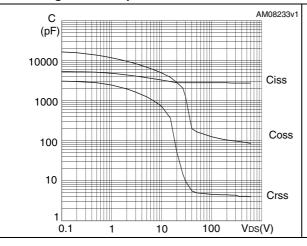


Figure 12. Normalized gate threshold voltage vs temperature

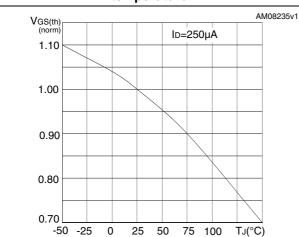


Figure 11. Output capacitance stored energy

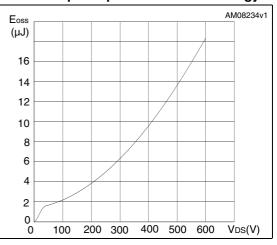


Figure 13. Normalized on-resistance vs temperature

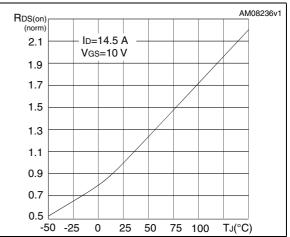
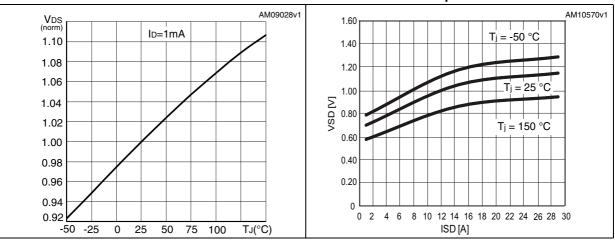




Figure 14. Normalized $\rm V_{DS}$ vs temperature

Figure 15. Source-drain diode forward vs temperature





Test circuits 3

Figure 16. Switching times test circuit for resistive load

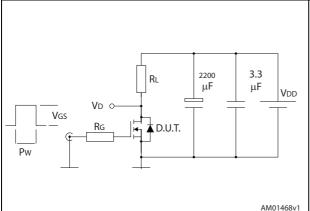


Figure 18. Test circuit for inductive load switching and diode recovery times

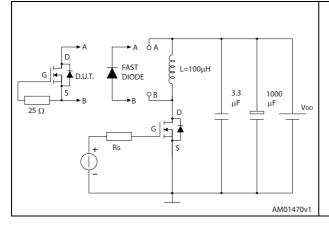


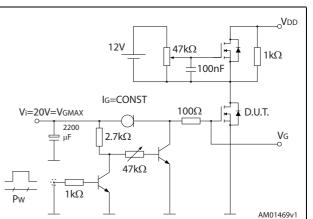
Figure 20. Unclamped inductive waveform

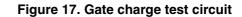
VD

ldм

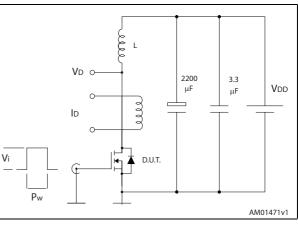
lр

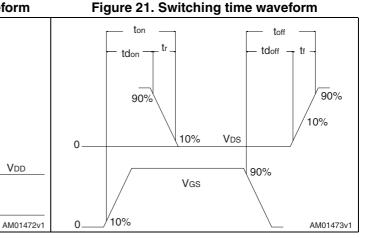
V(BR)DSS











Vdd

DocID023785 Rev 3

Vdd

4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK[®] is an ST trademark.



Dim		mm		
Dim.	Min.	Тур.	Max.	
A	4.40		4.60	
A1	0.03		0.23	
b	0.70		0.93	
b2	1.14		1.70	
с	0.45		0.60	
c2	1.23		1.36	
D	8.95		9.35	
D1	7.50			
E	10		10.40	
E1	8.50			
е		2.54		
e1	4.88		5.28	
Н	15		15.85	
J1	2.49		2.69	
L	2.29		2.79	
L1	1.27		1.40	
L2	1.30		1.75	
R		0.4		
V2	0°		8°	

Table 8. D²PAK (TO-263) mechanical data



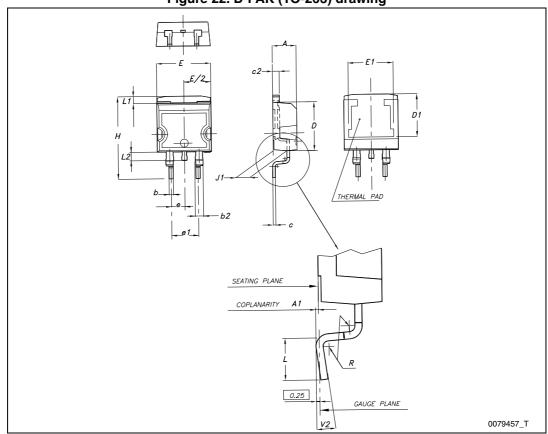
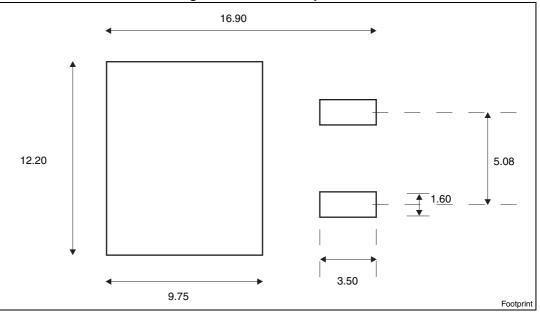


Figure 22. D²PAK (TO-263) drawing

Figure 23. D²PAK footprint^(a)



a. All dimensions are in millimeters



Dim.	mm.						
	Min.	Тур.	Max.				
А	4.85		5.15				
A1	2.20		2.60				
b	1.0		1.40				
b1	2.0		2.40				
b2	3.0		3.40				
С	0.40		0.80				
D	19.85		20.15				
E	15.45		15.75				
е	5.30	5.45	5.60				
L	14.20		14.80				
L1	3.70		4.30				
L2		18.50					
ØP	3.55		3.65				
ØR	4.50		5.50				
S	5.30	5.50	5.70				

Table 9. TO-247 mechanical data



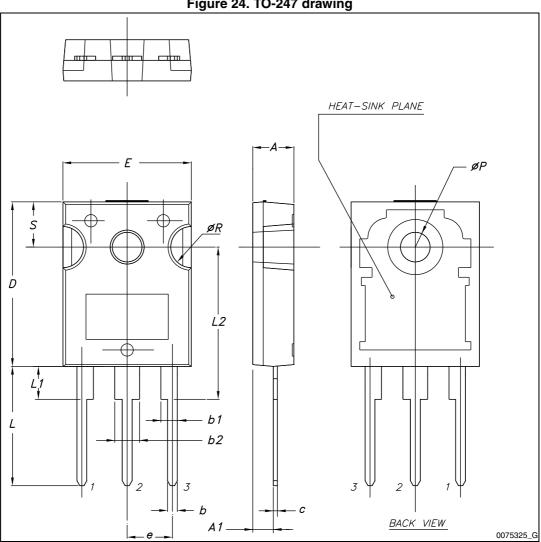


Figure 24. TO-247 drawing



5 Packaging mechanical data

	Таре		-	Reel		
Dim.	m	ım	Dim	mm		
	Min.	Max.	— Dim.	Min.	Max.	
A0	10.5	10.7	Α		330	
B0	15.7	15.9	В	1.5		
D	1.5	1.6	С	12.8	13.2	
D1	1.59	1.61	D	20.2		
Е	1.65	1.85	G	24.4	26.4	
F	11.4	11.6	Ν	100		
K0	4.8	5.0	Т		30.4	
P0	3.9	4.1				
P1	11.9	12.1		Base qty	1000	
P2	1.9	2.1		Bulk qty	1000	
R	50					
Т	0.25	0.35				
W	23.7	24.3				

Table 10. D²PAK (TO-263) tape and reel mechanical data



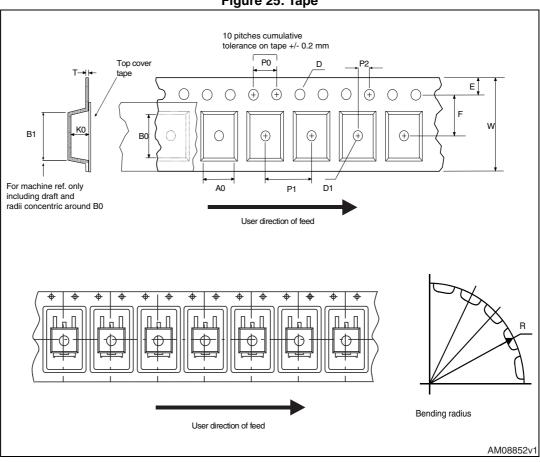
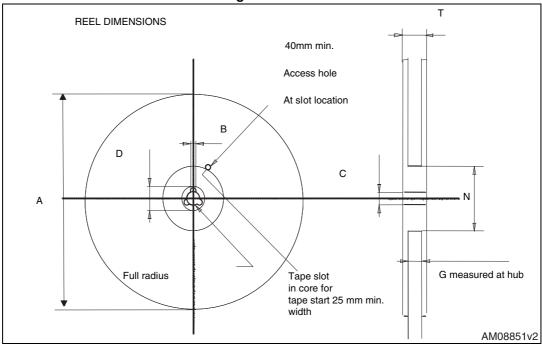


Figure 25. Tape

Figure 26. Reel





6 Revision history

Date	Revision	Changes
24-Oct-2012	1	Initial release.
01-Jul-2013	2	 Updated Figure 1: Internal schematic diagram. Added Section 2.1: Electrical characteristics (curves).
02-Oct-2013	3	 Modified: E_{AS} in <i>Table 4</i>, C_{oss eq.} typical value in <i>Table 6</i>, <i>Figure 13</i> Minor text changes

Table 11. Document revision history



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